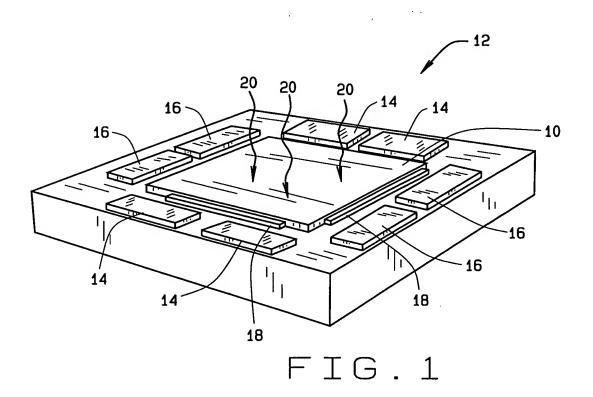
TITLÉ: METHOD FOR MONITORING PRODUCTION OF PIXEL DETECTORS
AND DETECTORS PRODUCED THEREBY
INVENTOR: AARON COUTURE, ET.AL.
DOCKET: 134665
ATTY: ALAN L. CASSEL; PHONE: (314) 621-5070

1/4



TITLE: METHOD FOR MONITORING PRODUCTION OF PIXEL DETECTORS AND DETECTORS PRODUCED THEREBY INVENTOR: AARON COUTURE, ET.AL. DOCKET: 134665
ATTY: ALAN L. CASSEL; PHONE: (314) 621-5070

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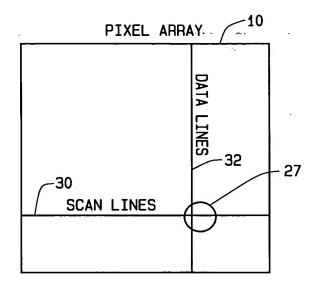


FIG.2

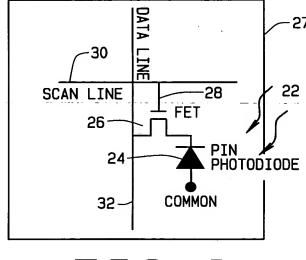
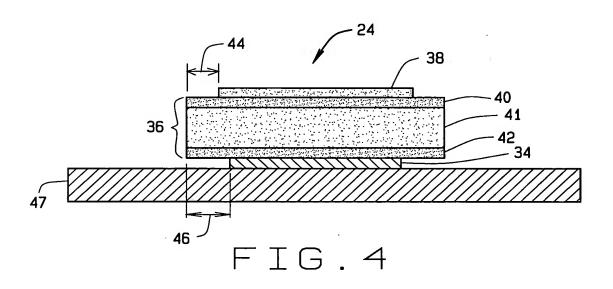


FIG.3

TITLE: METHOD FOR MONITORING PRODUCTION OF PIXEL DETECTORS
AND DETECTORS PRODUCED THEREBY
INVENTOR: AARON COUTURE, ET.AL.
DOCKET: 134665
ATTY: ALAN L. CASSEL; PHONE: (314) 621-5070

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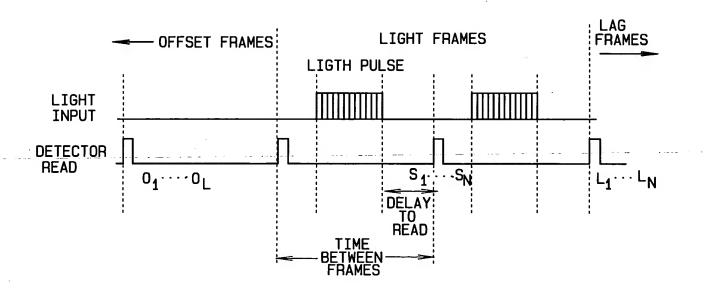


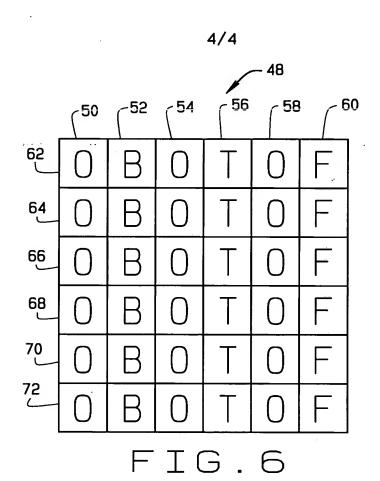
FIG.5

TITLE: METHOD FOR MONITORING PRODUCTION OF PIXEL DETECTORS AND DETECTORS PRODUCED THEREBY

INVENTOR: AARON COUTURE, ET.AL.

DOCKET: 134665

ATTY: ALAN L. CASSEL; PHONE: (314) 621-5070



200 202 -- 210 FET DEPOSTITION FEED BACK TO DIODE 204 -AND FET DEPOSITION CONDITIONS DIODE DEPOSITION - 208 206 ~ DATA ANALYSIS FOR PANEL PERFORMANCE TEST P+ LAYER QUALITY 212 N+ LAYER QUALITY • FET QUALITY SCINTILLATOR DEPOSITION USING PIXEL MONITOR 214 X-RAY TEST FIG.7